



FIS 1000

biax



RAM.

FIS 1000_{biax}

The Inspection System FIS 1000 _{biax} is especially optimized for defect recognition in biaxial lines. This means our system can be used in MDO (Machine Direction Orientation) as well as in TDO (Transverse Direction Orientation) area.

The technical description will be identical to FIS 1000 system.

The Inspection System FIS 1000 is especially optimized for defect recognition in films.

With this absolutely reliable and high efficient inspections system surface defects can be recognized in a range of 50mm up to 10m material width.

FIS 1000 detects, classifies, documents and records optical defects at films.

For illumination is possible fluoresced line lamps, LED line lamps for reflected light, transmitted light and light or dark field.

The defects are automatically classified such as gels, burning particles, fish eyes, dirt, etc..

Picture of the defects can be shown later on with RAM_PAT.

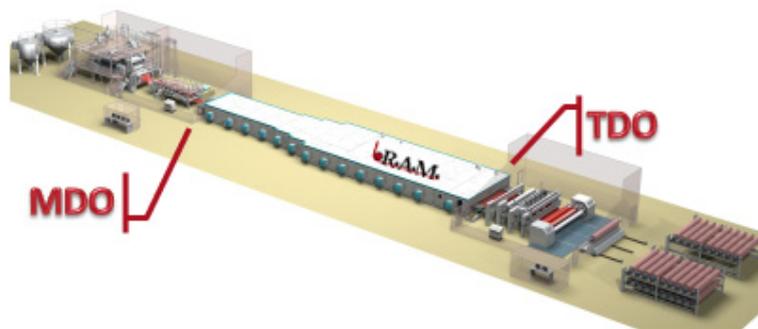
It is possible to defined as much classifiers (size and type) as you want.

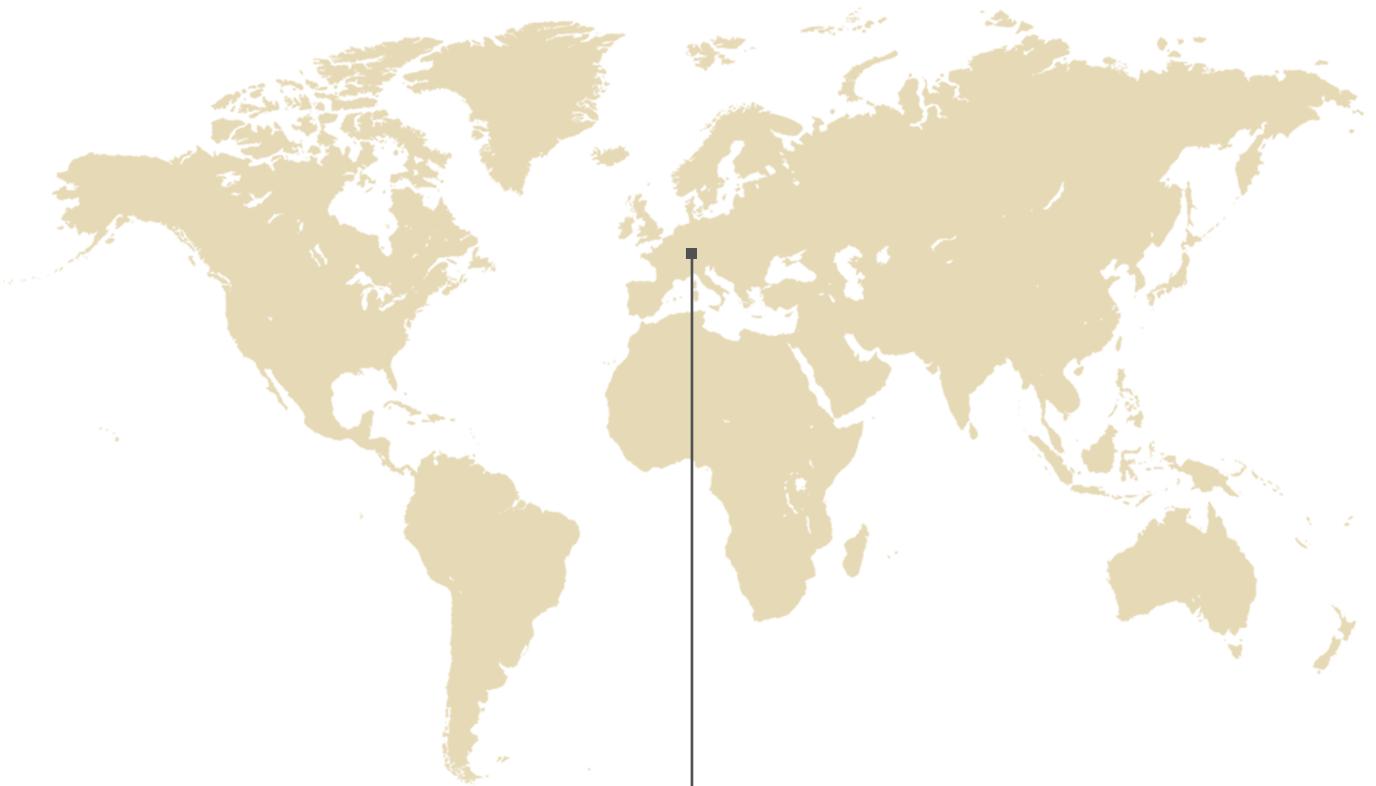
This "High End System" is able to differ any defect explicitly.

Users can typecast Defects only by using their pictures and sort then by classes.

The classifier will automatically calculate all parameter for this free learned defect class.

The system can also handle several slits, also with different widths, and assign them different order numbers.





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